



Refrigerants

Application Note

Environmental

Authors

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Introduction

Fast GC analysis of refrigerant impurities in CFC-22 is achieved in less than 50 seconds using an Agilent PoraPLOT U column and Agilent 490 Micro GC.



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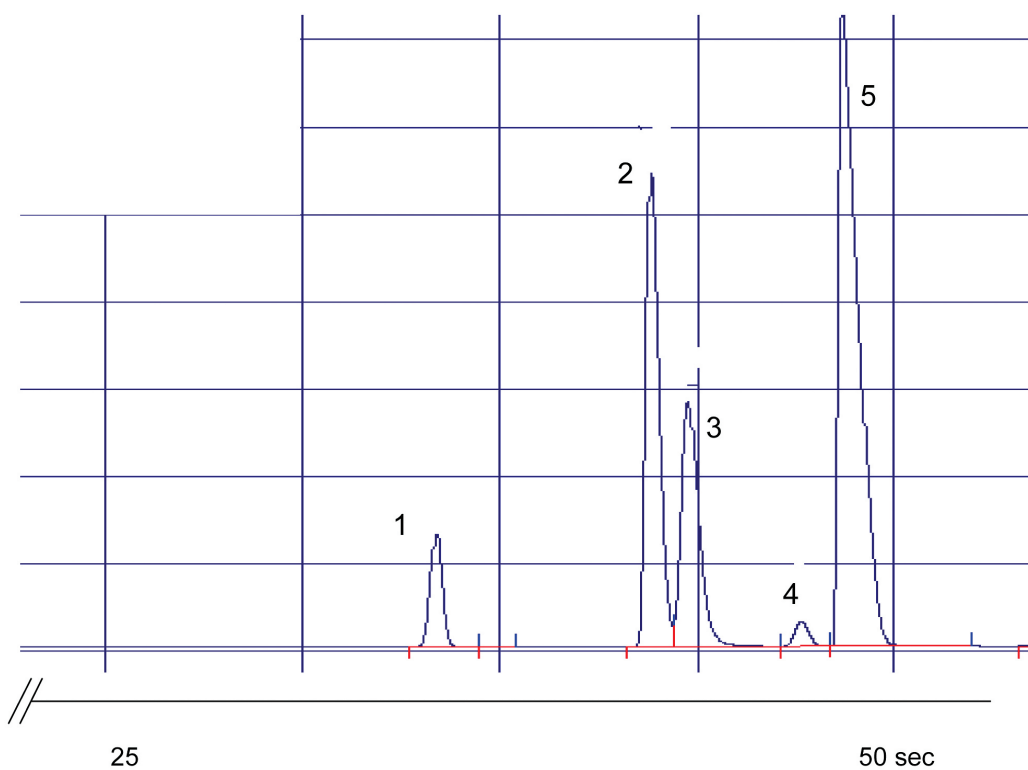
Conditions

Technique : Micro GC
Column : Agilent PoraPLOT U, 25 mm x 10 m fused silica
Temperature : 119 °C
Carrier Gas : Helium
Pressure program : 100 kPa, 5 s → 250 kPa, 200 kPa/min
Injector : chip injector heated, 100 °C
Injection time : 5 ms
Detector : chip TCD, Sensitivity: med
Concentration Range : % level

Courtesy : Mario Voglino
Stuart Wallman, A-GAS (UK) Ltd

Peak identification

1. air
2. CFC 143A
3. CFC 125
4. CFC 134A
5. CFC 22



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This information is subject to change without notice.

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